Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination
09/846,091	HAYNES ET AL.
Examiner	Art Unit
Benjamin P. Blumel	1648

Benjamin P. Blumel

SEARCHED				
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
SEQ ID NO	0:1 search by TIC			

SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
East	1/9/2007	BPB
Pubmed	1/9/2007	ВРВ